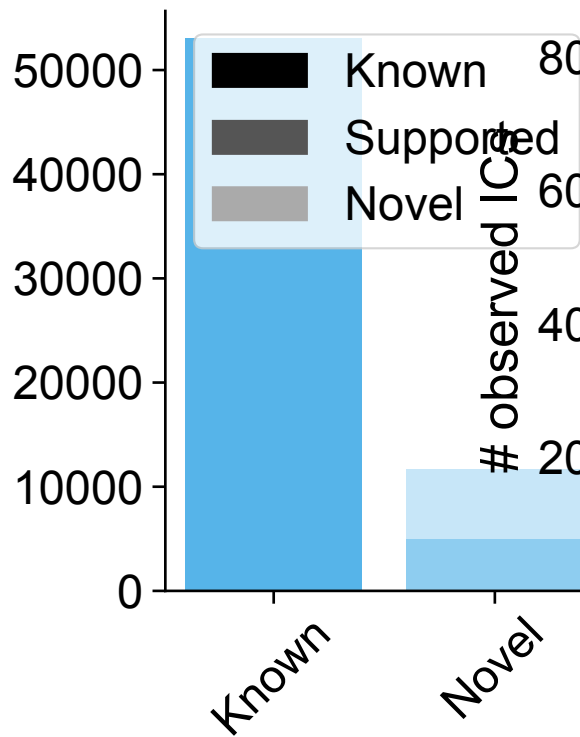


observed TSSs



observed ICs

